

10050776
01/18/02

U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

1m2

APPL NUM 10050776	FILING DATE 01/18/2002	CLASS 358	SUBCLASS 7.2	GAU 2633	EXAMINER S. A. A.
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**CONTINUING DATA VERIFIED: No					
FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-056547 03/01/2001					
PG-PUB		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO	
35 USC 119 conditions met		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no		520.41064X00	
Verified and Acknowledged Examiners's initials		US			
TITLE : Apparatus and method for inspecting defects					

U.S. DEPT. OF COMM./PAT. & TM.-PTO-426L (Rev. 12-94)

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NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg. Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
PREPARED FOR ISSUE			
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